

Notice of References Cited	Application/Control No. 10/629,280		Applicant(s)/Patent Under Reexamination YUN ET AL.	
	Examiner Thao P. Le		Art Unit 2818	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-6,232,184	05-2001	Wang et al.	438/265
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NON-PATENT DOCUMENTS

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